



# **FQD7N10 / FQU7N10**

### 100V N-Channel MOSFET

#### **General Description**

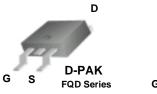
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as audio amplifiers, high efficiency switching DC/DC converters, and DC motor control.

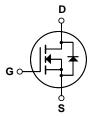
#### **Features**

- 5.8A, 100V,  $R_{DS(on)} = 0.35\Omega$  @ $V_{GS} = 10$  V
- Low gate charge (typical 5.8 nC)
- Low Crss (typical 10 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









# **Absolute Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQD7N10 / FQU7N10	Units
V <sub>DSS</sub>	Drain-Source Voltage		100	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C)		5.8	Α
			3.67	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	23.2	Α
$V_{GSS}$	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		50	mJ
I <sub>AR</sub>	Avalanche Current	alanche Current (Note 1)		А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	2.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C)		25	W
	- Derate above 25°C		0.2	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		5.0	°C/W
$R_{\theta JA}$	JA Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

\* When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C			0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V				1	μΑ
		V <sub>DS</sub> = 80 V, T <sub>C</sub> = 125°C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.9 A			0.28	0.35	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 2.9 \text{ A}$	(Note 4)		3.3		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz			190 60	250 75	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance				10	13	pF
Switchi	ing Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}$ = 50 V, $I_{D}$ = 7.3 A, $R_{G}$ = 25 $\Omega$ (Note 4, 5)		-	7	25	ns
t <sub>r</sub>	Turn-On Rise Time				24	60	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				13	35	ns
t <sub>f</sub>	Turn-Off Fall Time				19	50	ns
$Q_g$	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 7.3 \text{ A},$ $V_{GS} = 10 \text{ V}$ (Note 4, 5)			5.8	7.5	nC
$Q_{gs}$	Gate-Source Charge				1.4		nC
Q <sub>gd</sub>	Gate-Drain Charge				2.5		nC
	ource Diode Characteristics a	nd Maximum Ratings	S				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				5.8	Α	
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F					23.2	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 5.8 \text{ A}$				1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 7.3 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			70		ns
$Q_{rr}$	Reverse Recovery Charge				150		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.23mH,  $I_{AS}=5.8A,\ V_{DD}=25V,\ R_G=25\ \Omega,\ Starting\ T_J=25^{\circ}C$  3.  $I_{SD}\le 7.3A,\ di/dt\le 300A/\mu_S,\ V_{DD}\le BV_{DSS},\ Starting\ T_J=25^{\circ}C$  4. Pulse Test : Pulse width  $\le 300\mu_S,\ Duty\ cycle\le 2\%$  5. Essentially independent of operating temperature

# **Typical Characteristics**

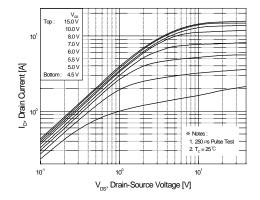


Figure 1. On-Region Characteristics

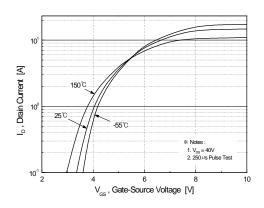


Figure 2. Transfer Characteristics

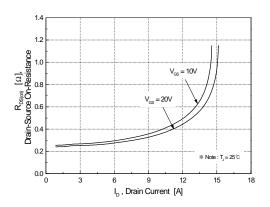


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

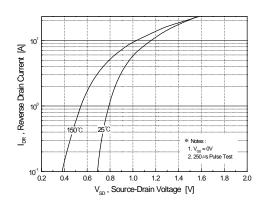


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

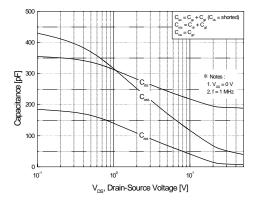


Figure 5. Capacitance Characteristics

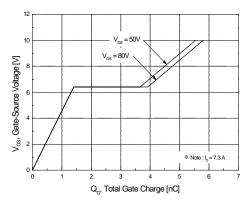
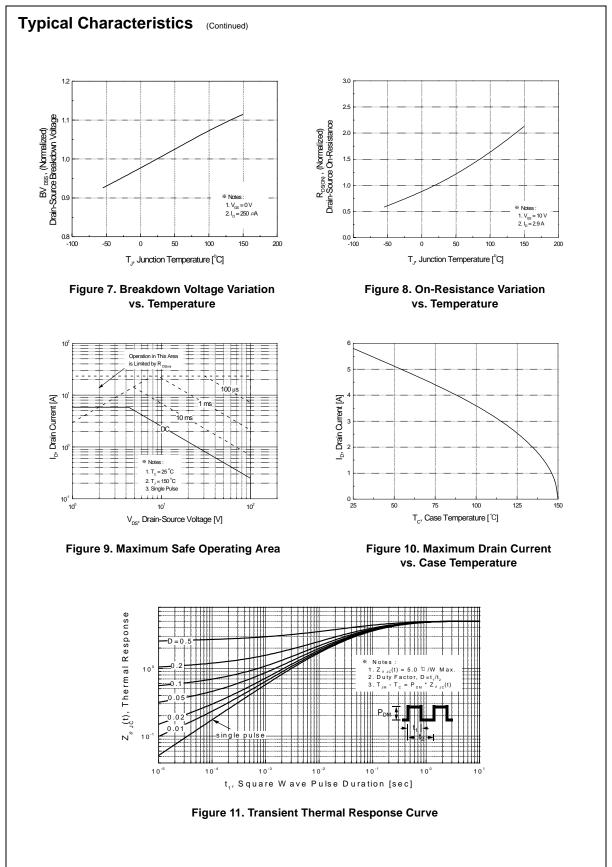


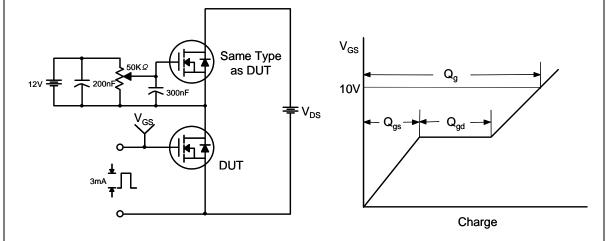
Figure 6. Gate Charge Characteristics

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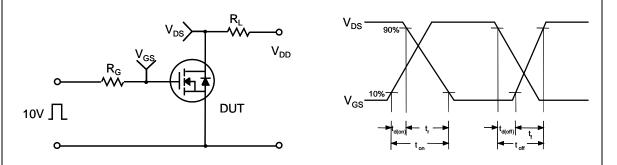


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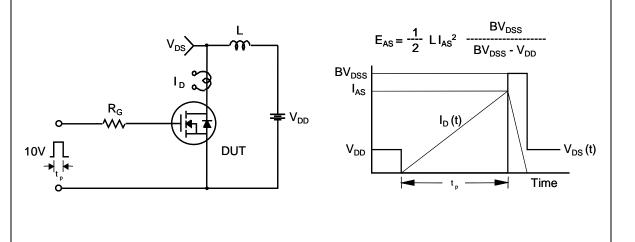
### **Gate Charge Test Circuit & Waveform**



### **Resistive Switching Test Circuit & Waveforms**

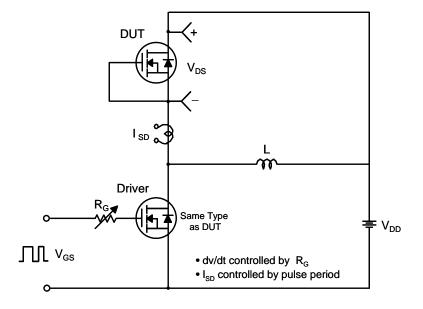


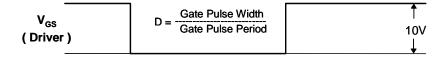
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

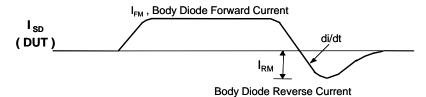


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# Peak Diode Recovery dv/dt Test Circuit & Waveforms







V<sub>DS</sub>
( DUT )

Body Diode Recovery dv/dt

V<sub>DD</sub>

V<sub>DD</sub>

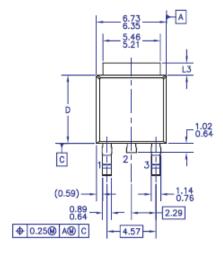
Body Diode

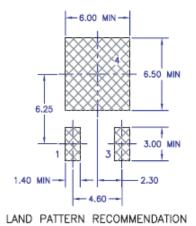
Forward Voltage Drop

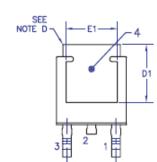
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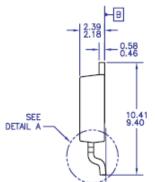
## **Mechanical Dimensions**

# D - PAK

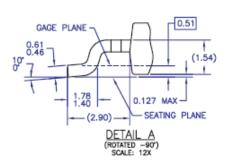




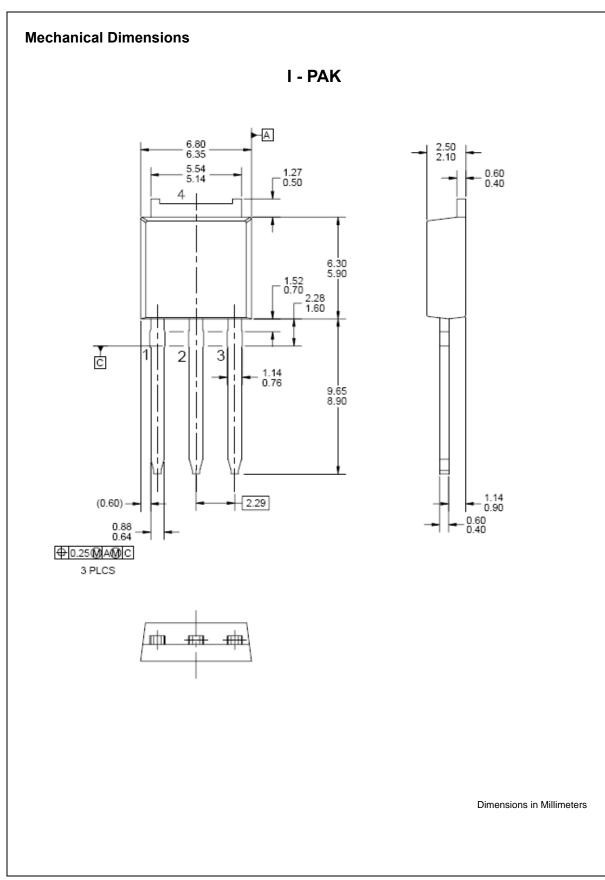




△ 0.10 B



Dimensions in Millimeters



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